

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed Herewith 2/24/00GROUP
2838 2829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

RR		Product Description for Ball Grid Array B1503-C3 from the Web Page of Roke Denzai America, Inc., 4 page
AS		
AT		

EXAMINER

rank Nguya

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed Herewith 2/24/00GROUP
Unknown 2829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
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FOREIGN PATENT DOCUMENTS

Foreign Treaty Documents								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AK	Product Description for Double Ended PROBES, 51052 SERIES, from the Web Page of Rika Denchi America, Inc., 1 page
AS	Product Description for Test Centers, RM 500 Series Probes, from the Web Page of Rika Denchi America, Inc., 1 page
AT	Product Description for Cost Effective Interconnections for High-HQ Products from the Web Page of Rika Denchi America, Inc., 1 page

EXAMINER

mh Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micro Technology, Inc.FILING DATE
Filed Herewith 2/24/00GROUP
UnknownU.S. PTO
09/512968

02/24/00

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA 09/032,184		Alkan et al.			2/22/98
VN	AB 5,495,667	3/5/96	Farnworth et al.	29	843	
	AC					
	AD					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AK	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page
AS	Good Things Come in Small BGACSP Packages from the Web Page of JORNIEN International Corporation, 1 page
AT	Product Description for Test Socket Connectors from the Web Page of JORNIEN International Corporation, 1 page

EXAMINER 2

mad Nguyen

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
Filed HerewithGROUP
2058829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA 4,560,216	12/24/85	Egawa			
VN	AB 4,754,555	7/5/88	Siltman			
VN	AC 5,475,317	12/12/95	Smith			
	AD					
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FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AL						
	AM						
	AN						
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

AR	Advertisement for Probe Technology from the Web Page of Interconnect Devices, Inc., 1 page
AS	Good Things Come in Small Packages from the Web Page of Johnson International Corporation, 1 page
AT	Product Description for Fast Series Connectors from the Web Page of Johnson International Corporation, 1 page

EXAMINER

DATE CONSIDERED

01/26/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000GROUP
Unknown2858
2829

U.S. PATENT DOCUMENTS

*Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
VN	AA	5,325,052	6/28/94	Yamashita			
	AB						
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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

Van Nguyen

DATE CONSIDERED

01/26/2001

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Page 2 of 1 1 of 1

Form PTO-11a		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M72-1383		SERIAL NO. 09512968	
LIST OF ART CITED BY APPLICANT (See Manual, Part 1, Section 1.2)				APPLICANT David Nguyen		FILING DATE February 24, 2000	
				GROUP 2829			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA 5,612,574	3/18/97	Summerton et al.				
VN	AB 5,718,333	2/17/98	Hopar et al.				
VN	AC 5,831,333	11/3/98	Meladi et al.				
VN	AD 5,919,548	7/6/99	Barton et al.				
VN	AE 5,551,283	9/3/96	Manassa et al.				
VN	AF 5,492,011	8/23/98	Ariano et al.				
	AG						
	AH						
	AJ						
FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
	AK						
	AL						
	AM						
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OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
VN	AP	"NTC and PTC Thermistors" http://www.thermopdisc.com/ntc/ppt.htm , 1/7/98, 2 pages.					
VN	AR	"D-5835 Linearized 4-Wire RTD Input" http://www.datalog.com/d5835.htm , 1/7/98, 2 pages.					
VN	AS	"RTD" http://www.instruments.com/rt.htm , 1/7/98, 3 pages.					
VN	AT	"Low Cost Thermal-Rubber (TM) uses thin film RTD" http://www.mesa.com/17824w.htm , 1/7/98, 1 page.					
VN	AU	"Silicon Processing for the VLSI Era: Volume 1 - Process Technology, Second Edition, S. Wolf et al., 2000, pps 23-25 and pps. 841-845. (month unavailable)					
EXAMINER <i>David Nguyen</i>				DATE CONSIDERED 01/22/04			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 608. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. 1622-1353		SERIAL NO. 09512 953	
LIST OF ART CITED BY APPLICANT (On several sheets if necessary)				APPLICANT Microsoft Technology, Inc.		PRIORITY GROUP 2829	
				FILING DATE February 24, 2000		PRIORITY GROUP 2829	
U.S. PATENT DOCUMENTS							
Examiner Initial	Class	Number	Date	Name	Class	Subject	Filing Date if Appropriate
VN	AA	3,710,251	1/9/1973	Hagge et al.			
	AB						
	AC						
	AD						
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
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	AL						
EXAMINER <i>rich Nguyen</i>				DATE CONSIDERED 01/22/04			
*EXAMINER: Indicate reference considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication if applicable.							

Form PTO-1449

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

ATTY. DOCKET NO.
1622-1763

SERIAL NO.
09512 959

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)

APPLICANT
Machon Technology, Inc.

FILING DATE
February 24, 2000

PRIORITY GROUP
255 2829

U.S. PATENT DOCUMENTS

Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA 4,912,600	3/1990	Jaeger et al.	361	70C	
VN	AB 5,436,494	7/1995	Moskals	257	45	
VN	AC 5,963,639	10/1999	Leuf et al.	340	8-17	
	AD					


OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER *anh Nguyen*

DATE CONSIDERED 01/22/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M27-1353		SERIAL NO. 05/512 658	
				APPLICANT Micron Technology, Inc.		PRIORITY GROUP 2553 7829	
				FILING DATE February 24, 2000			
U.S. PATENT DOCUMENTS							
Examiner Initial	Class	Subclass	Date	Name	Class	Subclass	Filing Date if Appropriate
W	AA	4 355 463	10/26/1982	Burns			
	AB						
	AC						
	AD						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
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EXAMINER <i>mh Nguy</i>				DATE CONSIDERED <i>01/22/04</i>			
<small>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</small>							

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OCT 01 2001

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
Micron Technology, Inc.FILING DATE
February 24, 2000PRIORITY GROUP
2858-2829

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Open
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U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA					
	AB					
	AC					
	AD					

OTHER REFERENCES (including Author, Title, Date, Portmanteau Pages, Etc.)

VN	AE	S/N: 09/032,184; Filed 2/27/98; Akram et al.; Amendment filed 12/18/00; CPA filed 7/28/00; Amendment filed 3/3/00; Amendment filed 8/23/99; Original Application filed 2/27/98; Pending Claims.
VN	AF	Advertisement for Probe Technology: www.idirect.com ; Interconnect Devices, Inc.; 1 page; 3/6/98
VN	AG	Good Things Come In Small BGA/CSP Packages: www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98
VN	AH	Product Description for Double Ended Probes, B1052 Series: www.testprobe.com/products/b1052.html ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AI	Product Description for Test Cerners, RM-500 Series Probes, www.testprobe.com/products/rm500.html ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AJ	Product Description for Cost Effective Interconnections for High I/O Products: www.testprobe.com/products/io.htm#b1303 ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AK	Product Description for Ball Grid Probe B1303-C3: www.testprobe.com/products/io.htm#b1303 ; Rika Denzhi America, Inc.; 1 page; 2/4/98.
VN	AL	Product Description for Test Socket Contacts: www.johnstech.com/4/handbook/page9.html ; 1 page; 3/5/98

EXAMINER

mark Nguyen

DATE CONSIDERED

10/25/2001

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

LIST OF ART CITED BY APPLICANT
(Use several sheets if necessary)APPLICANT
David R. HembreeFILING DATE
February 24, 2000GROUP
2829

U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA 3,440,407	4/22/69	Golstos et al.			
	AB 3,614,345	10/18/71	Quinn			
	AC 3,683,306	8/8/72	Bulthuis et al.			
	AD 4,332,081	8/1/82	Francis			
	AE 4,518,944	5/21/85	Faris			
	AF 4,703,556	11/3/87	Hubner			
	AG 5,141,334	8/25/92	Castles			
	AH 5,347,869	9/20/94	Shio et al.			
	AI 5,408,109	4/11/95	Whitney			
	AJ 5,436,648	7/25/95	McArthur et al.			
V	AK 5,448,437	8/29/95	Bantien et al.			

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Subclass	Translation	
						Yes	No
VN	AL 2338778	7/1977	France				
	AM 56-12521	2/1961	Kobayashi, Japan				
	AN 2-268482	11/1990	Yamanishi, Japan				
	AO						
	AP						

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

VN	AR	"Application Guide Temperature Sensors", Watlow Electrical Manufacturing Company Catalog, pp. 775-778, 1992/1993.
VN	AS	"In-Situ survey System of Resistive and Thermoelectric Properties of Either Pure or Mixed Materials in Thin Films Evaporated Under Ultra High Vacuum", Lechevallier, LeHuerou, Richon, Sarrau, & Gousault, J. Phys. III France, Vol. 5, pp. 409-418, 04/95 (Abstract only).
VN	AT	"Temperature Metrology for CD Control in DUV Lithography", Jeffrey Parker and Wayne Renken, pp. 111-112, 114, 116, 09/17/97.

EXAMINER


mark Nguy

DATE CONSIDERED

03/24/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M122-1383	SERIAL NO. 09512,968	
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				APPLICANT Micron Technology, Inc.		
				FILING DATE February 24, 2000	PRIORITY GROUP 2658 2829	
U.S. PATENT DOCUMENTS						
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate
VN	AA	6,004,471	12/21/1999	Chuang	—	—
VN	AB	5,550,526	8/27/1996	Mottahed	—	—
	AC					
	AD					
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)						
VN	AE	P. Van Zant, "Microchip Fabrication" (4th ed. 2000); pps 567-569.				
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	AG					
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	AJ	EV 18 2664 188				
	AK					
	AL					
EXAMINER 			DATE CONSIDERED 12/09/02			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Form 770		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY. DOCKET NO. M22-1353		SERIAL NO. 08512,955	
 LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT Micron Technology, Inc.		PRIORITY GROUP 2858-7829	
				FILING DATE February 24, 2000			
U.S. PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA 5,503,034	4/2/1995	Arbino et al.				
VN	AB 5,984,395	2/1/2000	Glovatsky et al.				
VN	AC 5,645,784	7/1/97	Angelopoulos et al.				
VN	AD 5,437,189	8/1/95	Brown et al.				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)							
	AE						
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EXAMINER <i>mark Ngump</i>			DATE CONSIDERED 09/03/04				
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 602. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							

TECHCENTER 2800

Form PTO-1449		<div style="border: 1px solid black; border-radius: 50%; padding: 5px; display: inline-block;"> JAN 28 2002 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE </div>		ATTY. DOCKET NO. M22-1363		SERIAL NO. 09/512,968	
LIST OF ART CITED BY APPLICANT (Use separate sheets if necessary)				APPLICANT David Hembree		FILING DATE February 24, 2000	
				GROUP 2858 2829			

U.S. PATENT DOCUMENTS							
*Examiner Initial	Document Number	Date	Name	Class	Subclass	Filing Date if Appropriate	
VN	AA	5,612,574	3/18/97	Summerfelt et al.			/
	AB	5,719,333	2/17/98	Hosoi et al.			
	AC	5,831,333	11/3/98	Mañadi et al.			
	AD	5,919,548	7/8/99	Barron et al.			
	AE	5,551,283	9/3/98	Manaka et al.			
	AF	5,492,011	2/20/98	Amano et al.			
	AG						
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FOREIGN PATENT DOCUMENTS							
Document Number	Date	Country	Class	Subclass	Translation		
					Yes	No	
AK							
AL							
AM							
AO							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
VN	AP		"NTC and PTC Thermistors" ; http://www.thermodisc.com/ntcptc.html ; 1/7/98; 2 pages.
VN	AR		"DI-5B35 Linearized 4-Wire RTD Input" ; http://www.dataq.com/di5b35.html ; 1/7/98; 2 pages.
VN	AS		"RTD"; http://www.rti-sensors.com/rtds.html ; 1/7/98; 3 pages.
VN	AT		"Low Cost Thermal-Ribbon (TM) uses thin film RTD"; http://www.minco.com/s17624nr.html ; 1/7/98; 1 page.
VN	AU		"Silicon Processing for the VLSI Era"; Volume 1 - Process Technology; Second Edition; S. Wolf et al.; 2000; pps 22-25 and pps. 841-845. (month unavailable)

EXAMINER <i>mtb Nguyen</i>	DATE CONSIDERED 05/30/2002
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